SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

- **Trimmed Offset Voltage: TLC279 . . . 900** μV Max at 25°C, $V_{DD} = 5 V$
- Input Offset Voltage Drift ... Typically 0.1 µV/Month, Including the First 30 Days
- Wide Range of Supply Voltages Over **Specified Temperature Range:** 0° C to 70° C . . . 3 V to 16 V -40°C to 85°C . . . 4 V to 16 V -55°C to 125°C . . . 4 V to 16 V
- Single-Supply Operation
- **Common-Mode Input Voltage Range Extends Below the Negative Rail (C-Suffix** and I-Suffix Versions)
- Low Noise . . . Typically 25 nV/ \sqrt{Hz} at f = 1 kHz
- **Output Voltage Range Includes Negative** Rail
- High Input Impedance . . . $10^{12} \Omega$ Typ
- **ESD-Protection Circuitry** •
- **Small-Outline Package Option Also** Available in Tape and Reel
- **Designed-In Latch-Up Immunity** •

description

The TLC274 and TLC279 quad operational amplifiers combine a wide range of input offset voltage grades with low offset voltage drift, high input impedance, low noise, and speeds approaching that of general-purpose BiFET devices.

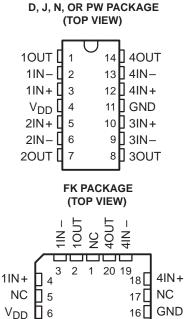
These devices use Texas Instruments silicon-gate LinCMOS™ technology, which provides offset voltage stability far exceeding the stability available with conventional metal-gate processes.

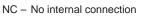
The extremely high input impedance, low bias currents, and high slew rates make these cost-effective devices ideal for applications which have previously been reserved for BiFET and NFET products. Four offset voltage grades are available (C-suffix and I-suffix types), ranging from the low-cost TLC274 (10 µV) to the highprecision TLC279 (900 µV). These advantages, in combination with good common-mode rejection and supply voltage rejection, make these devices a good choice for new state-of-the-art designs as well as for upgrading existing designs.

LinCMOS is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.







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2IN -2OUT S 30UT

NC

2IN+ Π 8

DISTRIBUTION OF TLC279 INPUT OFFSET VOLTAGE

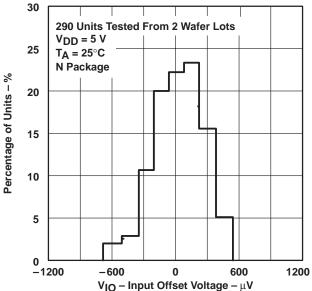
3IN

15**П**

14

NC

3IN +



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SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

description (continued)

In general, many features associated with bipolar technology are available on LinCMOS[™] operational amplifiers, without the power penalties of bipolar technology. General applications such as transducer interfacing, analog calculations, amplifier blocks, active filters, and signal buffering are easily designed with the TLC274 and TLC279. The devices also exhibit low voltage single-supply operation, making them ideally suited for remote and inaccessible battery-powered applications. The common-mode input voltage range includes the negative rail.

A wide range of packaging options is available, including small-outline and chip-carrier versions for high-density system applications.

The device inputs and outputs are designed to withstand –100-mA surge currents without sustaining latch-up.

The TLC274 and TLC279 incorporate internal ESD-protection circuits that prevent functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2; however, care should be exercised in handling these devices as exposure to ESD may result in the degradation of the device parametric performance.

The C-suffix devices are characterized for operation from 0°C to 70°C. The I-suffix devices are characterized for operation from -40°C to 85°C. The M-suffix devices are characterized for operation over the full military temperature range of -55°C to 125°C.

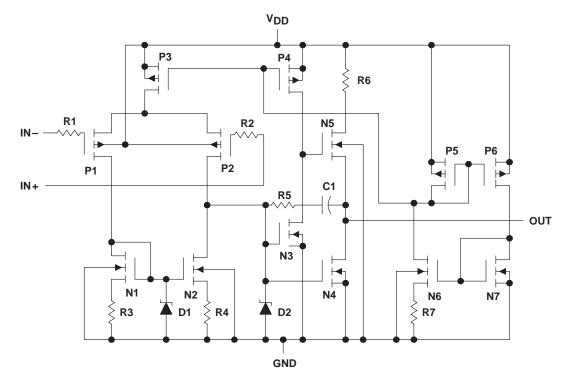
			PA	CKAGED DEV	ICES		СНІР
TA	V _{IO} max AT 25°C	SMALL OUTLINE (D)	CHIP CARRIER (FK)	CERAMIC DIP (J)	PLASTIC DIP (N)	TSSOP (PW)	FORM (Y)
0°C to 70°C	900 μV 2 mV	TLC279CD TLC274BCD	—	_	TLC279CN TLC274BCN		
	5 mV 10 mV	TLC274ACD TLC274CD	_	_	TLC274ACN TLC274CN		
–40°C to 85°C	900 μV 2 mV 5 mV 10 mV	TLC279ID TLC274BID TLC274AID TLC274ID			TLC279IN TLC274BIN TLC274AIN TLC274IN	 	
–55°C to 125°C	900 μV 10 mV	TLC279MD TLC274MD	TLC279MFK TLC274MFK	TLC279MJ TLC274MJ	TLC279MN TLC274MN		

AVAILABLE OPTIONS

The D package is available taped and reeled. Add R suffix to the device type (e.g., TLC279CDR).



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994



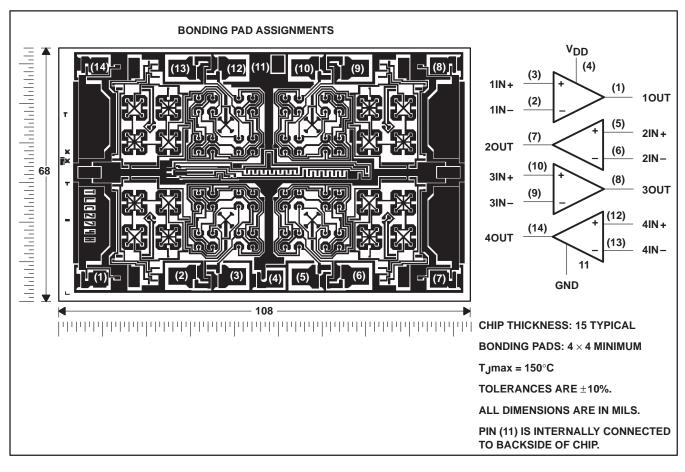
equivalent schematic (each amplifier)



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

TLC274Y chip information

These chips, when properly assembled, display characteristics similar to the TLC274C. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.





SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

$\begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{ccc} & \pm V_{DD} \\ & -0.3 \text{ V to } V_{DD} \\ & \pm 5 \text{ mA} \\ & \pm 30 \text{ mA} \end{array}$
Total current out of GND	45 mA
Duration of short-circuit current at (or below) 25°C (see Note 3) Continuous total dissipation	
Operating free-air temperature, T _A : C suffix	
l suffix	40°C to 85°C
M suffix	
Storage temperature range	
Case temperature for 60 seconds: FK package	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.

2. Differential voltages are at the noninverting input with respect to the inverting input.

3. The output may be shorted to either supply. Temperature and/or supply voltages must be limited to ensure that the maximum dissipation rating is not exceeded (see application section).

		DISSIPATION F	CATING TABLE		
PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	494 mW	—
FK	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
J	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
N	1575 mW	12.6 mW/°C	1008 mW	819 mW	—
PW	700 mW	5.6 mW/°C	448 mW	_	—

DISSIPATION RATING TABLE

recommended operating conditions

		C SU	FFIX	I SUF	FIX	M SU	FFIX	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Supply voltage, V _{DD}		3	16	4	16	4	16	V
	$V_{DD} = 5 V$	-0.2	3.5	-0.2	3.5	0	3.5	V
Common-mode input voltage, VIC	V _{DD} = 10 V	-0.2	8.5	-0.2	8.5	0	8.5	v
Operating free-air temperature, T_A		0	70	-40	85	-55	125	°C



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	TA [†]	TLC274 TLC274	C, TLC2 BC, TLC		UNIT
						MIN	TYP	MAX	
		TI 00740	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	
		TLC274C	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			12	
		TI 007440	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		0.9	5	mV
M	hannel affect welter we	TLC274AC	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			6.5	
VIO	Input offset voltage	TI 007400	V _O = 1.4 V,	VIC = 0,	25°C		340	2000	
		TLC274BC	$R_{S} = 50 \Omega,$	$R_L = 10 k\Omega$	Full range			3000	
		TI 00700	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		320	900	μV
		TLC279C	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			1500	
αΛΙΟ	Average temperature coeffic offset voltage	cient of input			25°C to 70°C		1.8		μV/°C
					25°C		0.1		
10	Input offset current (see Not	te 4)	V _O = 2.5 V,	V _{IC} = 2.5 V	70°C		7	300	pА
					25°C		0.6		
ΙB	Input bias current (see Note	e 4)	V _O = 2.5 V,	VIC = 2.5 V	70°C		40	600	pА
					25°C	-0.2 to	-0.3 to		V
VICR	Common-mode input voltag	e range				4	4.2		
	(see Note 5)				Full range	-0.2 to 3.5			V
					25°C	3.2	3.8		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	0°C	3	3.8		V
					70°C	3	3.8		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	0°C		0	50	mV
					70°C		0	50	
					25°C	5	23		
AVD	Large-signal differential volt amplification	age	$V_{O} = 0.25 V \text{ to } 2 V,$	$R_L = 10 \ k\Omega$	0°C	4	27		V/mV
	ampinication				70°C	4	20		
					25°C	65	80		
CMRR	Common-mode rejection rat	tio	VIC = VICRmin		0°C	60	84		dB
					70°C	60	85		
					25°C	65	95		
ksvr	Supply-voltage rejection ration	0	$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	0°C	60	94		dB
	$(\Delta V_{DD}/\Delta V_{IO})$				70°C	60	96		
					25°C		2.7	6.4	
IDD	Supply current (four amplifie	ers)	$V_{O} = 2.5 V$, No load	$V_{IC} = 2.5 V,$	0°C		3.1	7.2	mA
			INUIUau		70°C	1	2.3	5.2	

[†] Full range is 0°C to 70°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics at specified free-air temperature, V_{DD} = 10 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	τ _A †	TLC274 TLC274			UNIT
						MIN	TYP	MAX	
		TLC274C	V _O = 1.4 V,	VIC = 0,	25°C		1.1	10	
		1102740	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			12	
		TI 007440	V _O = 1.4 V,	VIC = 0,	25°C		0.9	5	mV
	have at a ffer a transfer and	TLC274AC	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			6.5	
VIO	Input offset voltage	TI 0074D0	V _O = 1.4 V,	VIC = 0,	25°C		390	2000	
		TLC274BC	$R_{S} = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			3000	
		TI 00700	V _O = 1.4 V,	V _{IC} = 0,	25°C		370	1200	μV
		TLC279C	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			1900	
αΛΙΟ	Average temperature coe input offset voltage	efficient of			25°C to 70°C		2		μV/°C
					25°C		0.1		
10	Input offset current (see	Note 4)	V _O =.5 V,	$V_{IC} = 5 V$	70°C		7	300	pА
					25°C		0.7		
IВ	Input bias current (see N	ote 4)	V _O = 5 V,	VIC = 5 V	70°C		50	600	pА
						-0.2	-0.3		
					25°C	to	to		V
VICR	Common-mode input vol	tage range				9	9.2		
ion	(see Note 5)				Full range	-0.2 to			V
					i un range	8.5			v
					25°C	8	8.5		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	0°C	7.8	8.5		V
					70°C	7.8	8.4		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	0°C		0	50	mV
					70°C		0	50	
					25°C	10	36		
AVD	Large-signal differential	voltage	$V_{O} = 1 V \text{ to } 6 V,$	$R_L = 10 \ k\Omega$	0°C	7.5	42		V/mV
	amplification		-		70°C	7.5	32		
					25°C	65	85		
CMRR	Common-mode rejection	ratio	$V_{IC} = V_{ICR}min$		0°C	60	88		dB
					70°C	60	88		
					25°C	65	95		
ksvr	Supply-voltage rejection	ratio	$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	0°C	60	94		dB
0.11	$(\Delta V_{DD}/\Delta V_{IO})$			2	70°C	60	96		
					25°C	1	3.8	8	
IDD	Supply current (four amp	lifiers)	$V_{O} = 5 V$,	$V_{IC} = 5 V,$	0°C		4.5	8.8	mA
50		,	No load		70°C		3.2	6.8	

[†] Full range is 0°C to 70°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	TAT		4I, TLC2 4BI, TL(UNIT
						MIN	TYP	MAX	
		TI 00741	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	
		TLC274I	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			13	
		TLC274AI	V _O = 1.4 V,	VIC = 0,	25°C		0.9	5	mV
Vie	Input offect voltage	TLC274AI	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			7	
VIO	Input offset voltage	TLC274BI	V _O = 1.4 V,	VIC = 0,	25°C		340	2000	
		TLC274DI	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			3500	μV
		TLC279I	V _O = 1.4 V,	V _{IC} = 0,	25°C		320	900	μv
		1202791	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			2000	
ανιο	Average temperature coeffic offset voltage	ent of input			25°C to 85°C		1.8		μV/°C
	lenut effect summert (ess Net	. 4)	N 05.V	N 05N	25°C		0.1		- 0
10	Input offset current (see Note	e 4)	V _O = 2.5 V,	V _{IC} = 2.5 V	85°C		24	1000	pА
	Innut high ourrent (and Note	4)			25°C		0.6		~ ^
IВ	Input bias current (see Note	4)	V _O = 2.5 V,	VIC = 2.5 V	85°C		200	2000	pА
M	Common-mode input voltage	erange			25°C	-0.2 to 4	-0.3 to 4.2		V
VICR	(see Note 5)	-			Full range	-0.2 to 3.5			V
					25°C	3.2	3.8		
VOH	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	-40°C	3	3.8		V
					85°C	3	3.8		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	-40°C		0	50	mV
					85°C		0	50	
					25°C	5	23		
AVD	Large-signal differential volta amplification	ge	$V_{O} = 0.25 V$ to 2 V,	$R_L = 10 \ k\Omega$	-40°C	3.5	32		V/mV
	ampinoation				85°C	3.5	19		
					25°C	65	80		
CMRR	Common-mode rejection rati	0	$V_{IC} = V_{ICR}min$		-40°C	60	81		dB
					85°C	60	86		
	Ourseling and a starting of				25°C	65	95		
k SVR	Supply-voltage rejection ratio)	$V_{DD} = 5 V$ to 10 V,	V _O = 1.4 V	-40°C	60	92		dB
					85°C	60	96		
					25°C		2.7	6.4	
IDD	Supply current (four amplifie	rs)	$V_{O} = 2.5 V$, No load	V _{IC} = 2.5 V,	-40°C		3.8	8.8	mA
					85°C		2.1	4.8	

[†] Full range is -40° C to 85° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics at specified free-air temperature, V_{DD} = 10 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	т _А †		4I, TLC2 4BI, TL0		UNIT
						MIN	TYP	MAX	
		TLC274I	V _O = 1.4 V,	VIC = 0,	25°C		1.1	10	
		1102741	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			13	mV
		TLC274AI	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		0.9	5	mv
Min	Innut offent veltere	TLC274AI	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			7	
VIO	Input offset voltage	TLC274BI	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		390	2000	
		1102/461	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			3500	μV
		TLC279I	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		370	1200	μv
		1202791	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			2900	
αVIO	Average temperature coeffici offset voltage	ent of input			25°C to 85°C		2		μV/°C
	leave affect average (as a blate				25°C		0.1		- 4
10	Input offset current (see Note	: 4)	V _O = 5 V,	$V_{IC} = 5 V$	85°C		26	1000	pА
l	leave bies summer (see Niste	4)			25°C		0.7		- 4
IВ	Input bias current (see Note	4)	V _O = 5 V,	VIC = 5 V	85°C		220	2000	pА
						-0.2	-0.3		
					25°C	to	to		V
VICR	Common-mode input voltage (see Note 5)	range				9	9.2		
	(see Note 5)				Full range	-0.2 to			v
					l'annange	8.5			
					25°C	8	8.5		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	-40°C	7.8	8.5		V
					85°C	7.8	8.5		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	-40°C		0	50	mV
					85°C		0	50	
					25°C	10	36		
AVD	Large-signal differential volta amplification	ge	$V_{O} = 1 V \text{ to } 6 V,$	$R_L = 10 \ k\Omega$	-40°C	7	47		V/mV
	ampineation				85°C	7	31		
					25°C	65	85		
CMRR	Common-mode rejection ration	С	$V_{IC} = V_{ICR}min$		-40°C	60	87		dB
					85°C	60	88		
					25°C	65	95		
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$)	$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	-40°C	60	92		dB
					85°C	60	96		
				N 5.1	25°C		3.8	8	
IDD	Supply current (four amplifier	s)	$V_{O} = 5 V$, No load	V _{IC} = 5 V,	-40°C		5.5	10	mA
					85°C		2.9	6.4	

[†] Full range is -40° C to 85° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

	DADAMETED		TERT CON		+ +	TLC27	4M, TLC	279M	
	PARAMETER		TEST CONI	DITIONS	T _A †	MIN	TYP	MAX	UNIT
		TLC274M	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	
V	Insuit offent veltere	TLC274M	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			12	mV
VIO	Input offset voltage		V _O = 1.4 V,	$V_{IC} = 0,$	25°C		320	900	
		TLC279M	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			3750	μV
αΛΙΟ	Average temperature coefficie offset voltage	ent of input			25°C to 125°C		2.1		μV/°C
li o	Input offset current (see Note	4)	V _O = 2.5 V,	VIC = 2.5 V	25°C		0.1		pА
10	input onset current (see Note	4)	$V_{0} = 2.5 V,$	VIC = 2.5 V	125°C		1.4	15	nA
lun.	Input bias current (see Note /		V _O = 2.5 V,	V _{IC} = 2.5 V	25°C		0.6		pА
IB	Input bias current (see Note 4	;)	$v_0 = 2.5 v,$	vIC = 2.5 v	125°C		9	35	nA
	Common-mode input voltage	range			25°C	0 to 4	-0.3 to 4.2		V
VICR	(see Note 5)	-			Full range	0 to 3.5			V
					25°C	3.2	3.8		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	−55°C	3	3.8		V
					125°C	3	3.8		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	−55°C		0	50	mV
					125°C		0	50	
					25°C	5	23		
AVD	Large-signal differential voltage amplification	je	$V_{O} = 0.25 V \text{ to } 2 V,$	$R_L = 10 \ k\Omega$	−55°C	3.5	35		V/mV
	ampinication				125°C	3.5	16		
					25°C	65	80		
CMRR	Common-mode rejection ratio)	$V_{IC} = V_{ICR}min$		−55°C	60	81		dB
					125°C	60	84		
	Ourseling to the st				25°C	65	95		
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$		$V_{DD} = 5 V$ to 10 V,	V _O = 1.4 V	−55°C	60	90		dB
					125°C	60	97		
					25°C		2.7	6.4	
IDD	Supply current (four amplifiers	5)	$V_{O} = 2.5 V$, No load	$V_{IC} = 2.5 V,$	−55°C		4	10	mA
					125°C		1.9	4.4	

[†] Full range is -55° C to 125° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics at specified free-air temperature, V_{DD} = 10 V (unless) otherwise noted)

			TEST CON		+ +	TLC27	4M, TLC	279M	
	PARAMETER		TEST CON	DITIONS	TAT	MIN	TYP	MAX	UNIT
		TLC274M	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	mV
VIO	Input offset voltage	1027411	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			12	IIIV
۷IO	input onset voltage	TLC279M	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		370	1200	μV
		1627910	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			4300	μv
αΛΙΟ	Average temperature coefficie offset voltage	ent of input			25°C to 125°C		2.2		μV/°C
lio.	Input offset current (see Note	4)	V _O = 5 V,	VIC = 5 V	25°C		0.1		pА
10	Input onset current (see Note	4)	VO = 5 V,	AIC = 2 A	125°C		1.8	15	nA
lun.	Input bias current (see Note 4	`	V _O = 5 V,	V _{IC} = 5 V	25°C		0.7		pА
IВ	input bias current (see Note 4)	VO = 5 V,	AIC = 2 A	125°C		10	35	nA
) (Common-mode input voltage	range			25°C	0 to 9	-0.3 to 9.2		V
VICR	(see Note 5)	-			Full range	0 to 8.5			V
					25°C	8	8.5		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	−55°C	7.8	8.5		V
					125°C	7.8	8.4		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	−55°C		0	50	mV
					125°C		0	50	
					25°C	10	36		
AVD	Large-signal differential voltag amplification	le	$V_{O} = 1 V \text{ to } 6 V,$	$R_L = 10 \ k\Omega$	−55°C	7	50		V/mV
	ampinoation				125°C	7	27		
					25°C	65	85		
CMRR	Common-mode rejection ratio		$V_{IC} = V_{ICR}min$		−55°C	60	87		dB
					125°C	60	86		
					25°C	65	95		
k SVR	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$		$V_{DD} = 5 V$ to 10 V,	V _O = 1.4 V	−55°C	60	90		dB
					125°C	60	97		
					25°C		3.8	8	
IDD	Supply current (four amplifiers	5)	$V_{O} = 5 V$, No load	V _{IC} = 5 V,	−55°C		6.0	12	mA
					125°C		2.5	5.6	

[†] Full range is -55° C to 125° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B – SEPTEMBER 1987 – REVISED AUGUST 1994

operating characteristics at specified free-air temperature, V_{DD} = 5 V

	PARAMETER	TEST CONDITIONS			TLC274C, TLC274AC, TLC274AC, TLC274BC, TLC279C			UNIT
					MIN	TYP	MAX	
				25°C		3.6		
			VIPP = 1 V	0°C		4		
SR	Slow rate at unity gain	$R_{L} = 10 \Omega,$		70°C		3		\//ue
SK	Slew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C		2.9		V/μs
		<u><u></u></u>	VIPP = 2.5 V	0°C		3.1		
				70°C		2.5		
V _n	Equivalent input noise voltage	f = 1 kHz, See Figure 2	$R_{S} = 20 \Omega$,	25°C		25		nV/√Hz
				25°C		320		
Вом	Maximum output-swing bandwidth	$V_{O} = V_{OH},$ R _L = 10 k Ω ,	C _L = 20 _P F, See Figure 1	0°C		340		kHz
		TKL = 10 K32,	Occ righter	70°C		260		
				25°C		1.7		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	0°C		2		MHz
		occ riguic o		70°C		1.3		
		10	()	25°C		46°		
φm	Phase margin	V _I = 10 mV, C _L = 20 pF,	f = B ₁ ,	0°C		47°		
		,		70°C		44°		

operating characteristics at specified free-air temperature, V_{DD} = 10 V

	PARAMETER	TEST CONDITIONS			TLC274C, TLC2 TLC274A TLC274BC, TL	С,	UNIT
			_		MIN TYP	MAX	
				25°C	5.3		
			V _{IPP} = 1 V	0°C	5.9		
SR	Slew rate at unity gain	$R_L = 10 \Omega$,		70°C	4.3		V/μs
	Siew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C	4.6		v/µS
		U U	VIPP = 5.5 V	0°C	5.1		
				70°C	3.8		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C	25		nV/√Hz
				25°C	200		
Вом	Maximum output-swing bandwidth	$V_{O} = V_{OH},$ R _L = 10 k Ω ,	C _L = 20 _P F, See Figure 1	0°C	220		kHz
			Occ rigare r	70°C	140		
				25°C	2.2		
В ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	0°C	2.5		MHz
		occ rigare o		70°C	1.8		
		10	()	25°C	49°		
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 3	0°C	50°		
				70°C	46°		



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

	PARAMETER	ER TEST CONDITIONS		ТА	TLC274I, TLC274AI, TLC274BI, TLC279I			UNIT
					TLC274BI, TLC279	MAX		
				25°C		3.6		
			V _{IPP} = 1 V	-40°C		4.5		
00		$R_L = 10 k\Omega$,		85°C		2.8		1////
SR	Slew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C		2.9		V/μs
			VIPP = 2.5 V	-40°C		3.5		1
				85°C		2.3		1
v _n	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25		nV/√Hz
		V _O = V _{OH} , R _L = 10 kΩ,		25°C		320		
Вом	Maximum output-swing bandwidth		C _L = 20 _P F, See Figure 1	-40°C		380		kHz
		1 L = 10 K32,	Occ rigure r	85°C		250		1
				25°C		1.7		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	-40°C		2.6		MHz
		See Figure 5		85°C		1.2		1
		10	(5	25°C		46°		
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$		-40°C		49°		1
			eee . igure e	85°C		43°		1

operating characteristics at specified free-air temperature, V_{DD} = 5 V

operating characteristics at specified free-air temperature, V_{DD} = 10 V

PARAMETER		PARAMETER TEST CONDITIONS		TA	TLC274I, TLC TLC274BI, TL	UNIT							
					MIN TYP	MAX							
				25°C	5.3								
			$V_{IPP} = 1 V$	-40°C	6.7								
SR	Slew rate at unity gain	$R_L = 10 \Omega$,		85°C	4		1///10						
SK	Siew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C	4.6		V/μs						
		V _I pp = 5.5 V	U U	VIPP = 5.5 V	-40°C	5.8							
			85°C	3.5									
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C	25		nV/√Hz						
		$V_{O} = V_{OH}$					25°C	200					
ВОМ	Maximum output-swing bandwidth					$V_O = V_{OH},$ $R_L = 10 \text{ k}\Omega,$				C _L = 20 _P F, See Figure 1	-40°C	260	
			Occ righter	85°C	130		1						
				25°C	2.2								
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	-40°C	3.1		MHz						
		occ rigure o		85°C	1.7								
		10	<u> </u>	25°C	49°								
φ _m	Phase margin	$V_{I} = 10 \text{ mV},$				$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$			f = B ₁ , See Figure 3	-40°C	52°		
		$O_{L} = 20 \text{ pr}, \qquad 366 \text{ Figure 3}$		85°C	46°								



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	DADAMETER	TEAT OF		.	TLC274	4M, TLC	279M	LINUT							
	PARAMETER	TESTCO	ONDITIONS	TA	TLC274M, TLC MIN TYP 3.6 4.7 2.3 2.9 3.7 2 2 25 320 400 230 1.7 2.9 1.1 46° 40°	MAX	UNIT								
				25°C		3.6									
			VIPP = 1 V	-55°C		4.7									
SR	Slow rote at unity gain	$R_{L} = 10 k\Omega$,		125°C		2.3		1////10							
SK	Slew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C		2.9		V/μs							
		5	V _{IPP} = 2.5 V	-55°C		3.7									
								125°C		2					
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25		nV/√Hz							
		$V_{O} = V_{OH}$					25°C		320						
ВОМ	Maximum output-swing bandwidth					$V_O = V_{OH},$ $R_L = 10 k\Omega,$				C _L = 20 _P F, See Figure 1	−55°C		400		kHz
		125°C		230											
				25°C		1.7									
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	−55°C		2.9		MHz							
			See Figure 5		125°C		1.1								
		10	(25°C		46°									
φm	Phase margin	$V_{I} = 10 \text{ mV},$							VI = 10 mV, CL = 20 pF,	f = B ₁ , See Figure 3	−55°C		49°		
			2001 19410 0	125°C		41°									

operating characteristics at specified free-air temperature, V_{DD} = 10 V

		TEST OF		.	TLC274M, TLC MIN TYP 5.3 7.1 3.1 4.6 6.1 2.7 25 200 280 110 2.22 3.4 1.6 49° 5.3 52°	M, TLC	279M	LINUT			
	PARAMETER	TESTCO	ONDITIONS	TA		MAX	UNIT				
				25°C		5.3					
$ \begin{array}{c} R_L = 10 \ \Omega \ , \\ C_L = 20 \ pF, \\ See \ Figure \ 1 \end{array} $			VIPP = 1 V	−55°C		7.1					
	Slow rate at unity gain			125°C		3.1		V/µs			
			25°C		4.6		v/µs				
		VIPP = 5.5 V	-55°C		6.1						
				R _S = 20 Ω,	125°C		2.7				
v _n	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25		nV/√Hz			
		$V_{O} = V_{OH},$ R _I = 10 kΩ,			25°C		200				
Вом	Maximum output-swing bandwidth		C _L = 20 _P F, See Figure 1	−55°C		280		kHz			
		T(_ = 10 K32,	Occ riguie i	125°C		110					
		Jnity-gain bandwidth $V_{I} = 10 \text{ mV}, \qquad C_{L} = 20 \text{ pF},$ See Figure 3	25°C		2.2						
B ₁	Unity-gain bandwidth		C _L = 20 _P F,	−55°C		3.4		MHz			
				125°C		1.6					
			(25°C		49°					
φm	Phase margin	$V_{I} = 10 \text{ mV},$			$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 3	−55°C		52°		
				125°C		44°					



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

electrical characteristics, V_{DD} = 5 V, T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CON		т	LC274Y		
		TEST CON	TEST CONDITIONS		TYP	MAX	UNIT
VIO	Input offset voltage	$V_{O} = 1.4 V,$ R _S = 50 Ω ,	V _{IC} = 0, R _L = 10 kΩ		1.1	10	mV
lio	Input offset current (see Note 4)	V _O = 2.5 V,	V _{IC} = 2.5 V		0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 2.5 V,	V _{IC} = 2.5 V		0.6		pА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 4	-0.3 to 4.2		V
VOH	High-level output voltage	V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	3.2	3.8		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$	IOT = 0		0	50	mV
AVD	Large-signal differential voltage amplification	V _O = 0.25 V to 2 V,	$R_L = 10 \ k\Omega$	5	23		V/mV
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}min$		65	80		dB
k SVR	Supply-voltage rejection ratio $(\Delta V_{DD} / \Delta V_{IO})$	V _{DD} = 5 V to 10 V,	V _O = 1.4 V	65	95		dB
IDD	Supply current (four amplifiers)	V _O = 2.5 V, No load	V _{IC} = 2.5 V,		2.7	6.4	mA

electrical characteristics, V_{DD} = 10 V, T_A = 25°C (unless otherwise noted)

	PARAMETER		DITIONS	т	LC274Y		UNIT
			TEST CONDITIONS		TYP	MAX	UNIT
VIO	Input offset voltage	$V_{O} = 1.4 V,$ R _S = 50 Ω ,	$V_{IC} = 0,$ $R_L = 10 \text{ k}\Omega$		1.1	10	mV
Iю	Input offset current (see Note 4)	V _O = 5 V,	$V_{IC} = 5 V$		0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 5 V,	V _{IC} = 5 V		0.7		pА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 9	-0.3 to 9.2		V
∨он	High-level output voltage	V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	8	8.5		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$		0	50	mV
AVD	Large-signal differential voltage amplification	V _O = 1 V to 6 V,	$R_L = 10 \ k\Omega$	10	36		V/mV
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}min$		65	85		dB
k SVR	Supply-voltage rejection ratio ($\Delta V_{DD} / \Delta V_{IO}$)	V _{DD} = 5 V to 10 V,	V _O = 1.4 V	65	95		dB
I _{DD}	Supply current (four amplifiers)	V _O = 5 V, No load	V _{IC} = 5 V,		3.8	8	mA

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092B – SEPTEMBER 1987 – REVISED AUGUST 1994

operating characteristics, V_{DD} = 5 V, T_A = 25°C

PARAMETER		_	TEST CONDITIONS		TLC274Y			UNIT
	FARAMETER	AMETER TEST CONDITIONS		15	MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	$R_L = 10 k\Omega$,	C _L = 20 _P F,	VIPP = 1 V		3.6		V/µs
SK	Siew rate at unity gain	See Figure 1		VIPP = 2.5 V		2.9		ν/μ5
Vn	Equivalent input noise voltage	f = 1 kHz,	R _S = 20 Ω,	See Figure 2		25		nV/√Hz
BOM	Maximum output-swing bandwidth	V _O = V _{OH} , See Figure 1	C _L = 20 pF,	R _L = 10 kΩ,		320		kHz
В ₁	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 _P F,	See Figure 3		1.7		MHz
φ _m	Phase margin	V _I = 10 mV, See Figure 3	$f = B_1,$	C _L = 20 pF,		46°		

operating characteristics, V_{DD} = 10 V, T_A = 25°C

PARAMETER			TEST CONDITIONS		TLC274Y			UNIT
	FARAMETER		TEST CONDITIONS			TYP	MAX	UNIT
SR	Slew rate at unity gain	$R_L = 10 \text{ k}\Omega$,	C _L = 20 _P F,	VIPP = 1 V		5.3		V/µs
SK	Siew fate at unity gain	See Figure 1		VIPP = 5.5 V		4.6		ν/μ5
Vn	Equivalent input noise voltage	f = 1 kHz,	R _S = 20 Ω,	See Figure 2		25		nV/√Hz
B _{OM}	Maximum output-swing bandwidth	V _O = V _{OH} , See Figure 1	C _L = 20 _P F,	R _L = 10 kΩ,		200		kHz
В ₁	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 _P F,	See Figure 3		2.2		MHz
φ _m	Phase margin	V _I = 10 mV, See Figure 3	$f = B_1,$	C _L = 20 pF,		49°		

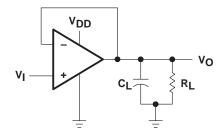


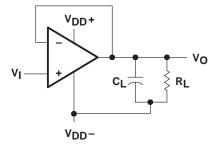
SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

PARAMETER MEASUREMENT INFORMATION

single-supply versus split-supply test circuits

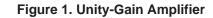
Because the TLC274 and TLC279 are optimized for single-supply operation, circuit configurations used for the various tests often present some inconvenience since the input signal, in many cases, must be offset from ground. This inconvenience can be avoided by testing the device with split supplies and the output load tied to the negative rail. A comparison of single-supply versus split-supply test circuits is shown below. The use of either circuit gives the same result.

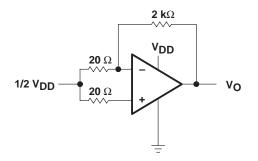


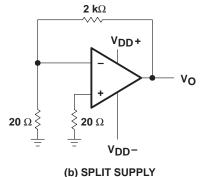




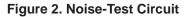
(b) SPLIT SUPPLY

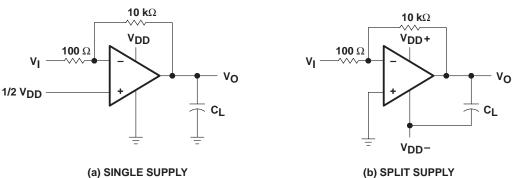






(a) SINGLE SUPPLY





a) SINGLE SUFFLI

Figure 3. Gain-of-100 Inverting Amplifier



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

PARAMETER MEASUREMENT INFORMATION

input bias current

Because of the high input impedance of the TLC274 and TLC279 operational amplifiers, attempts to measure the input bias current can result in erroneous readings. The bias current at normal room ambient temperature is typically less than 1 pA, a value that is easily exceeded by leakages on the test socket. Two suggestions are offered to avoid erroneous measurements:

- 1. Isolate the device from other potential leakage sources. Use a grounded shield around and between the device inputs (see Figure 4). Leakages that would otherwise flow to the inputs are shunted away.
- 2. Compensate for the leakage of the test socket by actually performing an input bias current test (using a picoammeter) with no device in the test socket. The actual input bias current can then be calculated by subtracting the open-socket leakage readings from the readings obtained with a device in the test socket.

One word of caution: many automatic testers as well as some bench-top operational amplifier testers use the servo-loop technique with a resistor in series with the device input to measure the input bias current (the voltage drop across the series resistor is measured and the bias current is calculated). This method requires that a device be inserted into the test socket to obtain a correct reading; therefore, an open-socket reading is not feasible using this method.

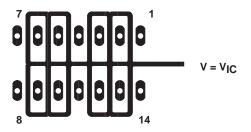


Figure 4. Isolation Metal Around Device Inputs (J and N packages)

low-level output voltage

To obtain low-supply-voltage operation, some compromise was necessary in the input stage. This compromise results in the device low-level output being dependent on both the common-mode input voltage level as well as the differential input voltage level. When attempting to correlate low-level output readings with those quoted in the electrical specifications, these two conditions should be observed. If conditions other than these are to be used, please refer to Figures 14 through 19 in the Typical Characteristics of this data sheet.

input offset voltage temperature coefficient

Erroneous readings often result from attempts to measure temperature coefficient of input offset voltage. This parameter is actually a calculation using input offset voltage measurements obtained at two different temperatures. When one (or both) of the temperatures is below freezing, moisture can collect on both the device and the test socket. This moisture results in leakage and contact resistance, which can cause erroneous input offset voltage readings. The isolation techniques previously mentioned have no effect on the leakage since the moisture also covers the isolation metal itself, thereby rendering it useless. It is suggested that these measurements be performed at temperatures above freezing to minimize error.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

PARAMETER MEASUREMENT INFORMATION

full-power response

Full-power response, the frequency above which the operational amplifier slew rate limits the output voltage swing, is often specified two ways: full-linear response and full-peak response. The full-linear response is generally measured by monitoring the distortion level of the output while increasing the frequency of a sinusoidal input signal until the maximum frequency is found above which the output contains significant distortion. The full-peak response is defined as the maximum output frequency, without regard to distortion, above which full peak-to-peak output swing cannot be maintained.

Because there is no industry-wide accepted value for significant distortion, the full-peak response is specified in this data sheet and is measured using the circuit of Figure 1. The initial setup involves the use of a sinusoidal input to determine the maximum peak-to-peak output of the device (the amplitude of the sinusoidal wave is increased until clipping occurs). The sinusoidal wave is then replaced with a square wave of the same amplitude. The frequency is then increased until the maximum peak-to-peak output can no longer be maintained (Figure 5). A square wave is used to allow a more accurate determination of the point at which the maximum peak-to-peak output is reached.

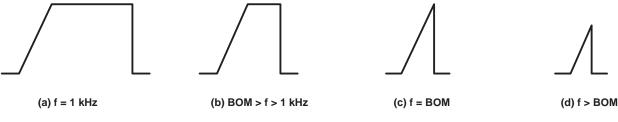


Figure 5. Full-Power-Response Output Signal

test time

Inadequate test time is a frequent problem, especially when testing CMOS devices in a high-volume, short-test-time environment. Internal capacitances are inherently higher in CMOS than in bipolar and BiFET devices and require longer test times than their bipolar and BiFET counterparts. The problem becomes more pronounced with reduced supply levels and lower temperatures.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

TYPICAL CHARACTERISTICS

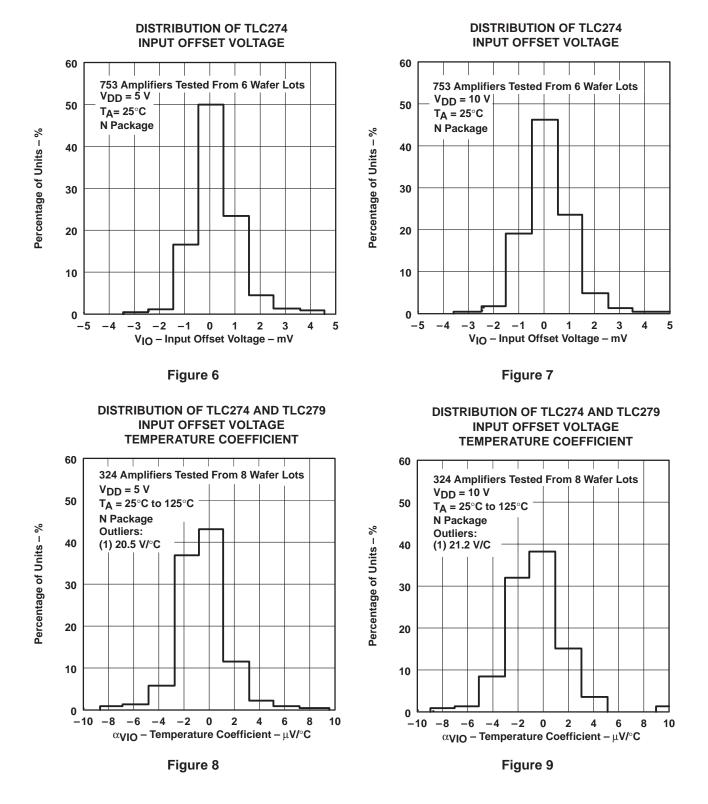
			FIGURE
VIO	Input offset voltage	Distribution	6, 7
ανιο	Temperature coefficient of input offset voltage	Distribution	8, 9
VOH	High-level output voltage	vs High-level output current vs Supply voltage vs Free-air temperature	10, 11 12 13
V _{OL}	Low-level output voltage	vs Common-mode input voltage vs Differential input voltage vs Free-air temperature vs Low-level output current	14, 15 16 17 18, 19
AVD	Large-signal differential voltage amplification	vs Supply voltage vs Free-air temperature vs Frequency	20 21 32, 33
I _{IB}	Input bias current	vs Free-air temperature	22
IIO	Input offset current	vs Free-air temperature	22
VIC	Common-mode input voltage	vs Supply voltage	23
IDD	Supply current	vs Supply voltage vs Free-air temperature	24 25
SR	Slew rate	vs Supply voltage vs Free-air temperature	26 27
	Normalized slew rate	vs Free-air temperature	28
VO(PP)	Maximum peak-to-peak output voltage	vs Frequency	29
В ₁	Unity-gain bandwidth	vs Free-air temperature vs Supply voltage	30 31
[¢] m	Phase margin	vs Supply voltage vs Free-air temperature vs Load capacitance	34 35 36
Vn	Equivalent input noise voltage	vs Frequency	37
	Phase shift	vs Frequency	32, 33

Table of Graphs



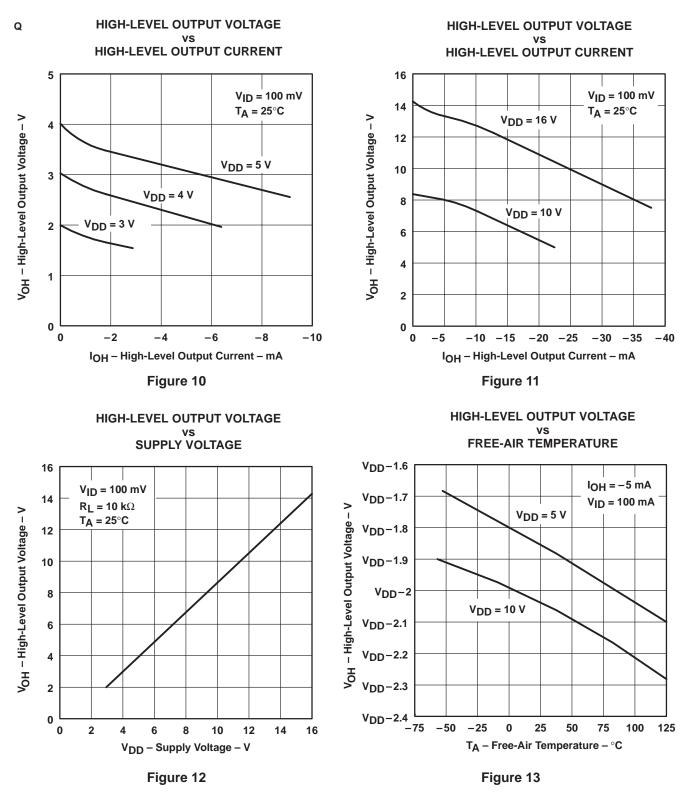
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TYPICAL CHARACTERISTICS





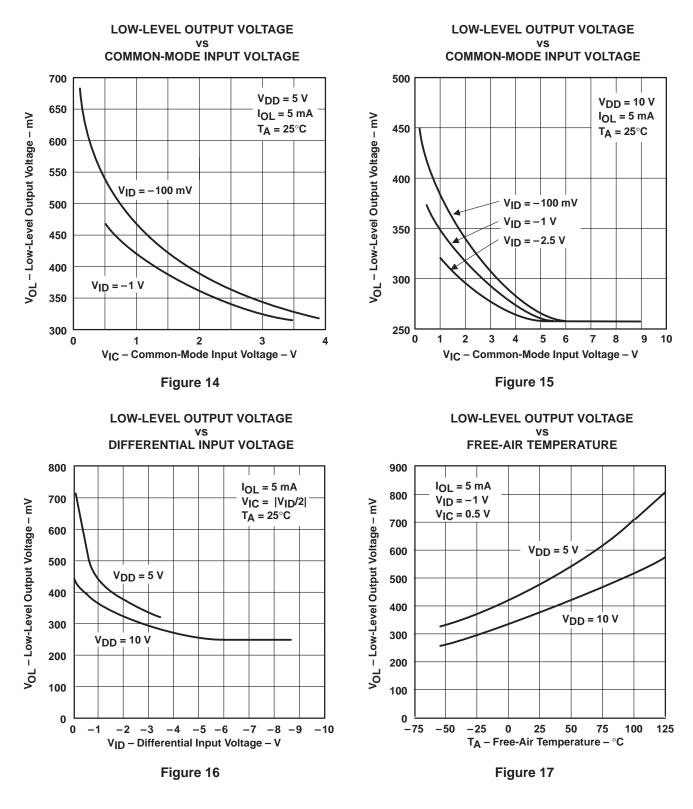
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TYPICAL CHARACTERISTICS[†]



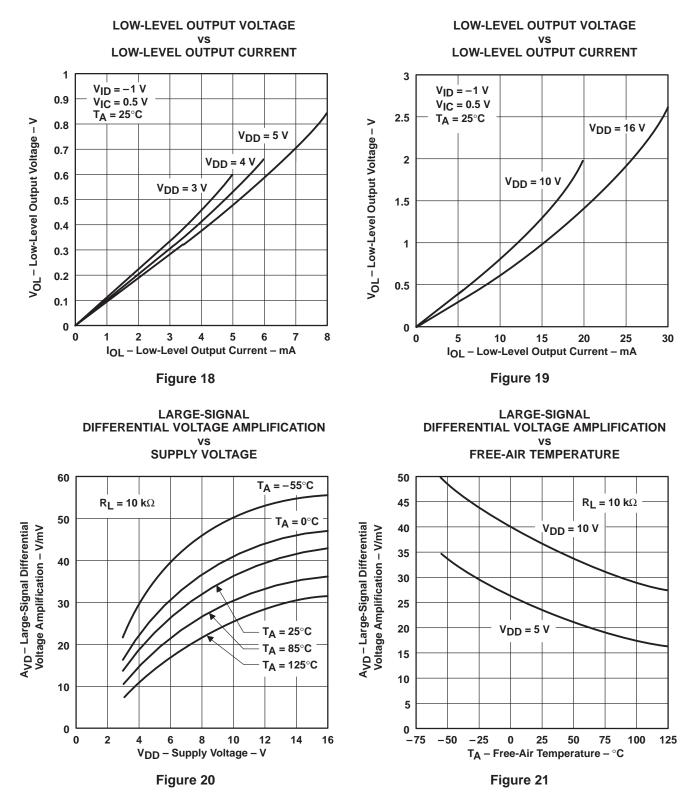
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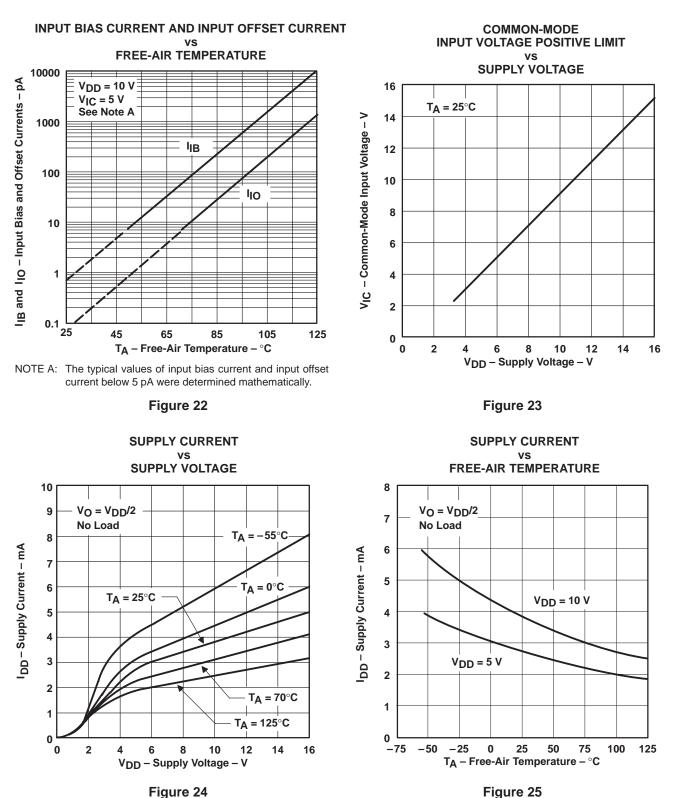
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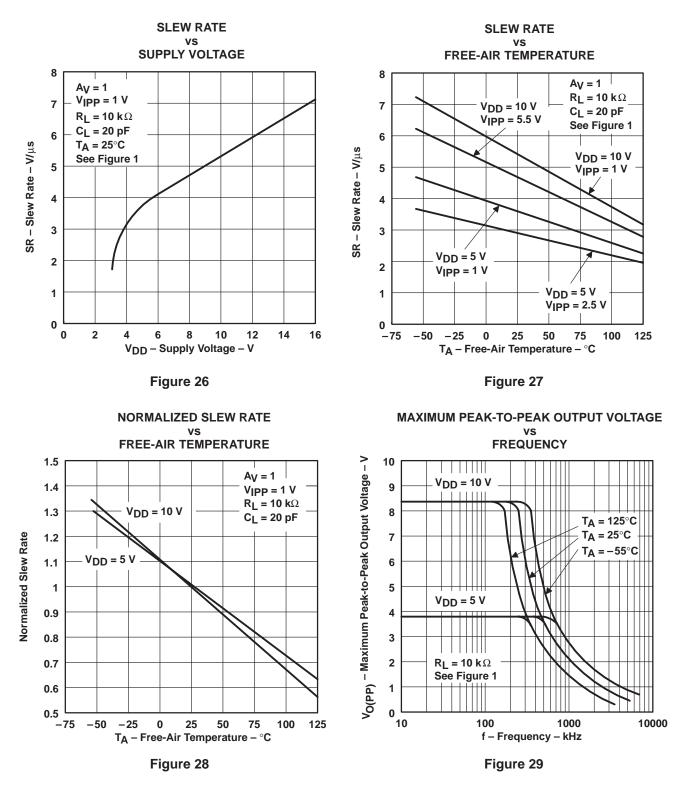
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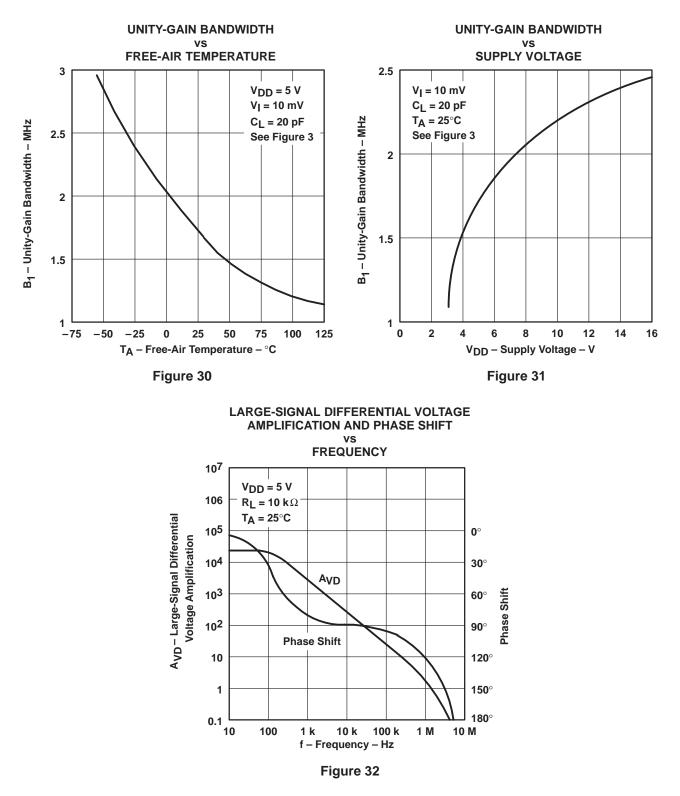
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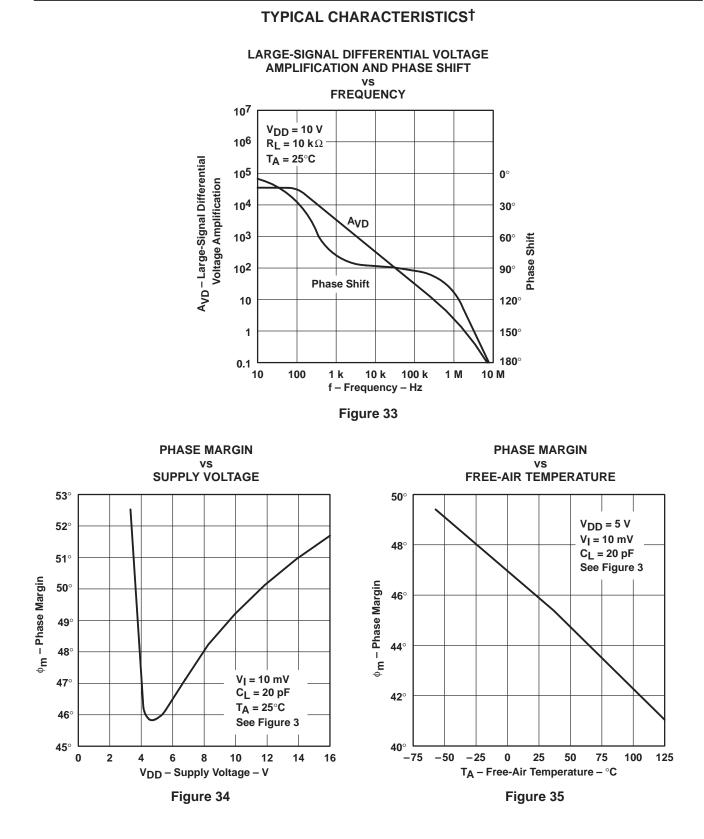
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TYPICAL CHARACTERISTICS[†]



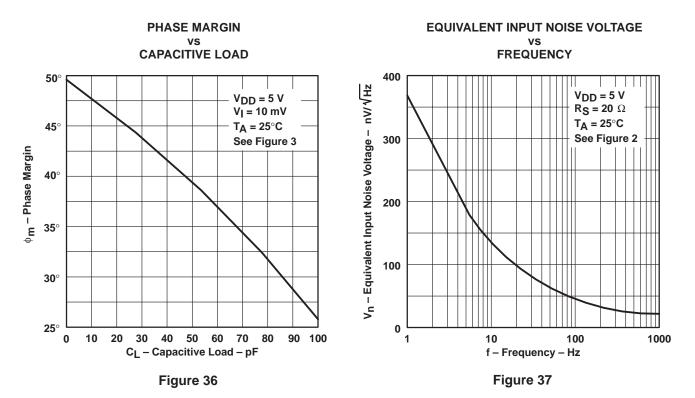
SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994





SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

TYPICAL CHARACTERISTICS





SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

APPLICATION INFORMATION

single-supply operation

While the TLC274 and TLC279 perform well using dual power supplies (also called balanced or split supplies), the design is optimized for single-supply operation. This design includes an input common-mode voltage range that encompasses ground as well as an output voltage range that pulls down to ground. The supply voltage range extends down to 3 V (C-suffix types), thus allowing operation with supply levels commonly available for TTL and HCMOS; however, for maximum dynamic range, 16-V single-supply operation is recommended.

Many single-supply applications require that a voltage be applied to one input to establish a reference level that is above ground. A resistive voltage divider is usually sufficient to establish this reference level (see Figure 38). The low input bias current of the TLC274 and TLC279 permits the use of very large resistive values to implement the voltage divider, thus minimizing power consumption.

The TLC274 and TLC279 work well in conjunction with digital logic; however, when powering both linear devices and digital logic from the same power supply, the following precautions are recommended:

- 1. Power the linear devices from separate bypassed supply lines (see Figure 39); otherwise the linear device supply rails can fluctuate due to voltage drops caused by high switching currents in the digital logic.
- 2. Use proper bypass techniques to reduce the probability of noise-induced errors. Single capacitive decoupling is often adequate; however, high-frequency applications may require R_C decoupling.

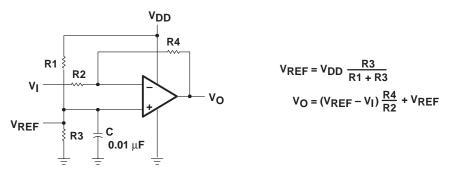
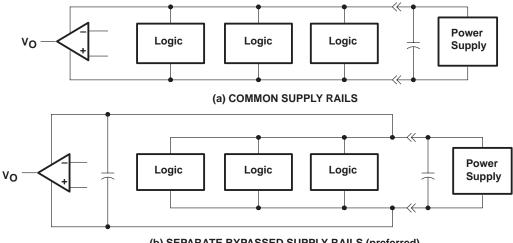


Figure 38. Inverting Amplifier With Voltage Reference



(b) SEPARATE BYPASSED SUPPLY RAILS (preferred)

Figure 39. Common Versus Separate Supply Rails



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

APPLICATION INFORMATION

input characteristics

The TLC274 and TLC279 are specified with a minimum and a maximum input voltage that, if exceeded at either input, could cause the device to malfunction. Exceeding this specified range is a common problem, especially in single-supply operation. Note that the lower range limit includes the negative rail, while the upper range limit is specified at $V_{DD} - 1$ V at $T_A = 25^{\circ}$ C and at $V_{DD} - 1.5$ V at all other temperatures.

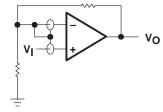
The use of the polysilicon-gate process and the careful input circuit design gives the TLC274 and TLC279 very good input offset voltage drift characteristics relative to conventional metal-gate processes. Offset voltage drift in CMOS devices is highly influenced by threshold voltage shifts caused by polarization of the phosphorus dopant implanted in the oxide. Placing the phosphorus dopant in a conductor (such as a polysilicon gate) alleviates the polarization problem, thus reducing threshold voltage shifts by more than an order of magnitude. The offset voltage drift with time has been calculated to be typically 0.1 μ V/month, including the first month of operation.

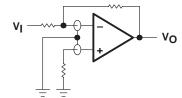
Because of the extremely high input impedance and resulting low bias current requirements, the TLC274 and TLC279 are well suited for low-level signal processing; however, leakage currents on printed-circuit boards and sockets can easily exceed bias current requirements and cause a degradation in device performance. It is good practice to include guard rings around inputs (similar to those of Figure 4 in the Parameter Measurement Information section). These guards should be driven from a low-impedance source at the same voltage level as the common-mode input (see Figure 40).

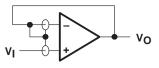
Unused amplifiers should be connected as grounded unity-gain followers to avoid possible oscillation.

noise performance

The noise specifications in operational amplifier circuits are greatly dependent on the current in the first-stage differential amplifier. The low input bias current requirements of the TLC274 and TLC279 result in a very low noise current, which is insignificant in most applications. This feature makes the devices especially favorable over bipolar devices when using values of circuit impedance greater than 50 k Ω , since bipolar devices exhibit greater noise currents.







(a) NONINVERTING AMPLIFIER

(b) INVERTING AMPLIFIER

(c) UNITY-GAIN AMPLIFIER

Figure 40. Guard-Ring Schemes

output characteristics

The output stage of the TLC274 and TLC279 is designed to sink and source relatively high amounts of current (see typical characteristics). If the output is subjected to a short-circuit condition, this high current capability can cause device damage under certain conditions. Output current capability increases with supply voltage.

All operating characteristics of the TLC274 and TLC279 were measured using a 20-pF load. The devices drive higher capacitive loads; however, as output load capacitance increases, the resulting response pole occurs at lower frequencies, thereby causing ringing, peaking, or even oscillation (see Figure 41). In many cases, adding a small amount of resistance in series with the load capacitance alleviates the problem.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

APPLICATION INFORMATION

output characteristics (continued)

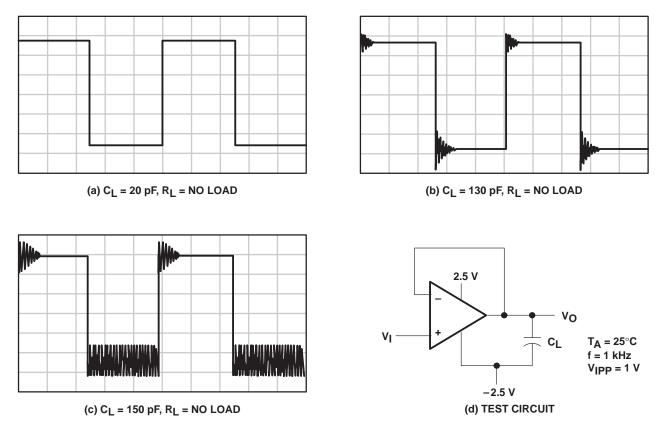


Figure 41. Effect of Capacitive Loads and Test Circuit

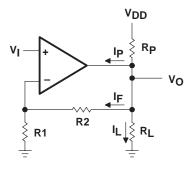
Although the TLC274 and TLC279 possess excellent high-level output voltage and current capability, methods for boosting this capability are available, if needed. The simplest method involves the use of a pullup resistor (R_P) connected from the output to the positive supply rail (see Figure 42). There are two disadvantages to the use of this circuit. First, the NMOS pulldown transistor N4 (see equivalent schematic) must sink a comparatively large amount of current. In this circuit, N4 behaves like a linear resistor with an on-resistance between approximately 60Ω and 180Ω , depending on how hard the op amp input is driven. With very low values of R_P, a voltage offset from 0 V at the output occurs. Second, pullup resistor R_P acts as a drain load to N4 and the gain of the operational amplifier is reduced at output voltage levels where N5 is not supplying the output current.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

APPLICATION INFORMATION

output characteristics (continued)





Ip = Pullup current required by the operational amplifier (typically 500 μ A)

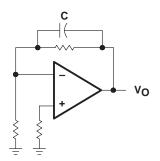


Figure 43. Compensation for Input Capacitance

Figure 42. Resistive Pullup to Increase VOH

feedback

Operational amplifier circuits nearly always employ feedback, and since feedback is the first prerequisite for oscillation, some caution is appropriate. Most oscillation problems result from driving capacitive loads (discussed previously) and ignoring stray input capacitance. A small-value capacitor connected in parallel with the feedback resistor is an effective remedy (see Figure 43). The value of this capacitor is optimized empirically.

electrostatic discharge protection

The TLC274 and TLC279 incorporate an internal electrostatic discharge (ESD) protection circuit that prevents functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2. Care should be exercised, however, when handling these devices as exposure to ESD may result in the degradation of the device parametric performance. The protection circuit also causes the input bias currents to be temperature-dependent and have the characteristics of a reverse-biased diode.

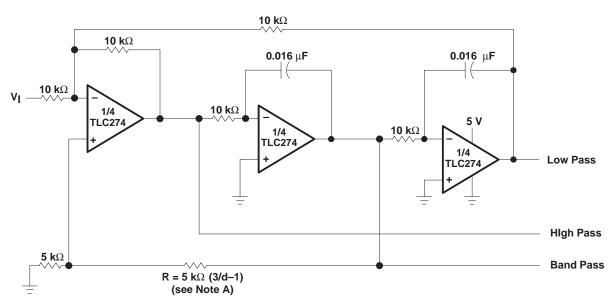
latch-up

Because CMOS devices are susceptible to latch-up due to their inherent parasitic thyristors, the TLC274 and TLC279 inputs and outputs were designed to withstand –100-mA surge currents without sustaining latch-up; however, techniques should be used to reduce the chance of latch-up whenever possible. Internal protection diodes should not, by design, be forward biased. Applied input and output voltage should not exceed the supply voltage by more than 300 mV. Care should be exercised when using capacitive coupling on pulse generators. Supply transients should be shunted by the use of decoupling capacitors (0.1 μ F typical) located across the supply rails as close to the device as possible.

The current path established if latch-up occurs is usually between the positive supply rail and ground and can be triggered by surges on the supply lines and/or voltages on either the output or inputs that exceed the supply voltage. Once latch-up occurs, the current flow is limited only by the impedance of the power supply and the forward resistance of the parasitic thyristor and usually results in the destruction of the device. The chance of latch-up occurring increases with increasing temperature and supply voltages.



SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994



APPLICATION INFORMATION



Figure 44. State-Variable Filter

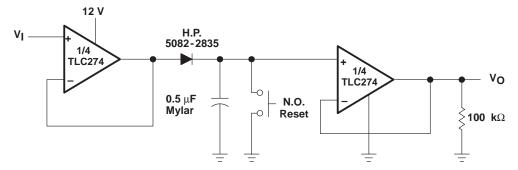
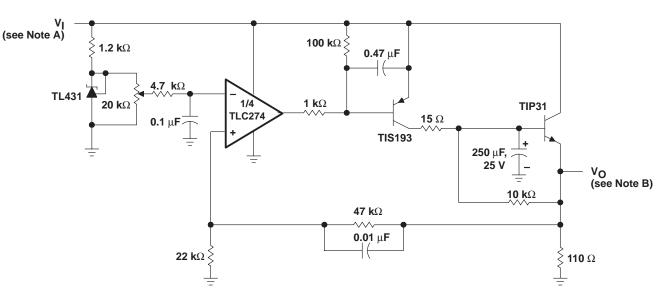


Figure 45. Positive-Peak Detector



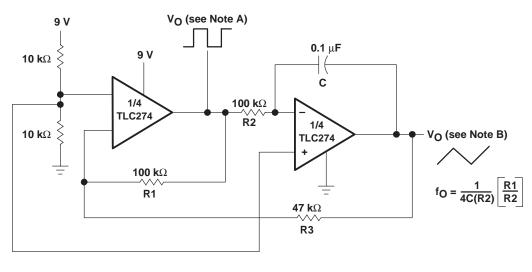
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APPLICATION INFORMATION

NOTES: B. $V_I = 3.5 V \text{ to } 15 V$ C. $V_O = 2 V$, 0 to 1 A

Figure 46. Logic-Array Power Supply



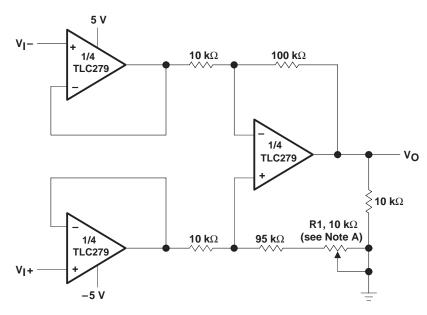
NOTES: A. $V_{O(PP)} = 8 V$ B. $V_{O(PP)} = 4 V$





SLOS092B - SEPTEMBER 1987 - REVISED AUGUST 1994

APPLICATION INFORMATION



NOTE C: CMRR adjustment must be noninductive.



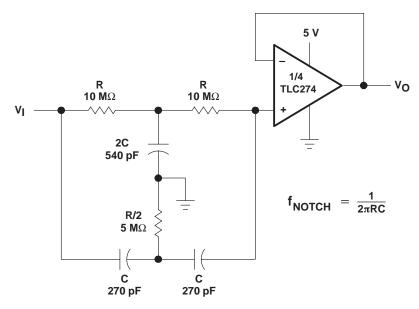


Figure 49. Single-Supply Twin-T Notch Filter



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